

<b>Notice of References Cited</b>	Application/Control No. 10/759,234		Applicant(s)/Patent Under Reexamination JIN ET AL.	
	Examiner Jonathan Liou		Art Unit 2672	Page 1 of 2

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,523,024 B2	02-2003	Yajima et al.	707/3
	C	US-			
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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Markus Niederost, Detection and reconstruction of buildings for a 3-D landscape model of Switzerland, 2000, Institute of Geodesy and photogrammetry(IGP), Swiss Federal Institute of Technology Zurich (ETHZ), Proceedings of UM3/2000 Workshop, Tokyo 2000. □□
	V	Markus Niederost, Reliable Reconstruction of Buildings for Digital Map Revision, 2000, Institute of Geodesy and photogrammetry(IGP), Swiss Federal Institute of Technology Zurich (ETHZ), International Archives of Photogrammetry and Remote Sensing, Vol. XXI
	W	Markus Niederost, Automated update of building information in maps using medium-scale imagery (1:15,000), 2001, Institute of Geodesy and photogrammetry(IGP), Swiss Federal Institute of Technology Zurich (ETHZ)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	Examiner Jonathan Liou	Art Unit 2672	Page 2 of 2

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	V <sub>2</sub>	Noroha, Nevatia, Detection and description of buildings from multiple aerial images, June 1997, Computer Vision and Pattern Recognition, Pages: 588-594
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